## Notice of References Cited Application/Control No. 10/715,045 Examiner Yuwen Pan Applicant(s)/Patent Under Reexamination SENDYK ET AL. Page 1 of 1 U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,006,804	02-2006	Clark et al.	455/105
*	В	US-6,594,473	07-2003	Dabak et al.	455/101
*	С	US-2001/0004585	06-2001	Tsujimoto, Ichiro	455/101
*	D	US-2003/0114108	06-2003	Frecassetti et al.	. 455/61
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	Ī	US-			
	J	US-			
	ĸ	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					·
	R					
	s					
	Т	•				

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	٧							
	w							
	×							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.